



ECLIPSE L300N/L300ND L200N/L200ND

FPD/LSI Inspection Microscopes



ECLIPSE



L300N

For ø300 mm wafer/
Episcopic illumination type



L300ND

For 17-inch FPD/
Episcopic and Diascopic illumination type



L200N

For ø200 mm wafer/
Episcopic illumination type



L200ND

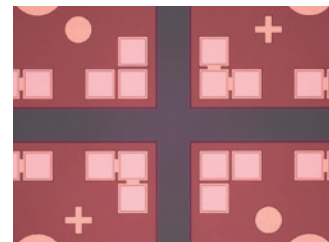
For ø200 mm wafer/
Episcopic and Diascopic illumination type

Enhanced observation performance and operation

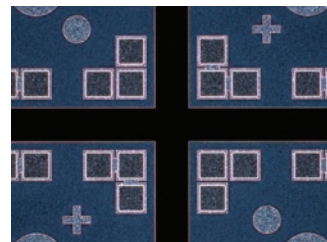
Epi-fluorescence observation widens inspection range—including 365 nm UV excitation

- Highly beneficial when inspecting semiconductor resist residues and organic electroluminescence displays.
- Various observation methods such as brightfield, darkfield, simple polarizing, and DIC are possible on all models.
- With the L300ND/L200ND, diascopic illumination capability adds the illumination through transparent substrates.

*L300N/L300ND/L200ND only



Brightfield observation
of wafer pattern



Darkfield observation



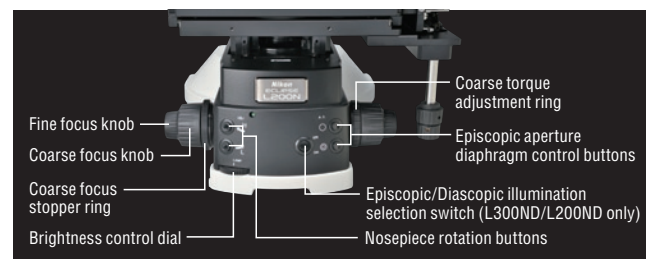
DIC observation



Epi-fluorescence observation of
organic substance on wafer

Front operation with easy access

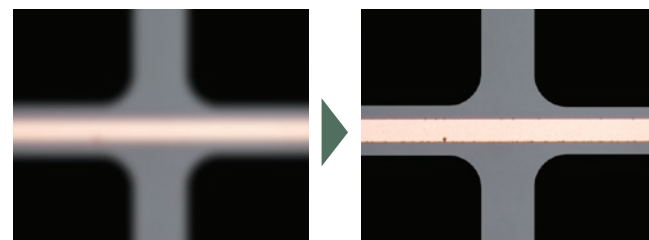
- Minimizes fatigue during lengthy observations



Fine focus knob
Coarse focus knob
Coarse focus stopper ring
Brightness control dial
Coarse torque adjustment ring
Episcopic aperture diaphragm control buttons
Episcopic/Diascopic illumination selection switch (L300ND/L200ND only)
Nosepiece rotation buttons

Target for easier focusing

- Insert a focusing target in the optical path to easily focus on low-contrast samples, such as bare wafers.



Stronger safeguard against contamination

- Antistatic coatings applied to the body, stage, eyepiece tube and other various controls
- Prevents damage to samples and contributes to higher yields

Observation at optimum eyepoint level

- Ultra-wide 25-mm field of view and eyepiece angle adjustment between 0° and 30°
- Operators can adjust eyepoint level to ensure a comfortable viewing position



Fixed-position X-Y fine movement control

- Allows for stage movements and focusing to be carried out with ease



The X-Y fine movement controls are positioned close to the operator.

Illumination

LED

Compact LED illuminators are power saving and achieve long life.



LV-LL LED Lamphouse

Intensilight

• Motorized mercury precentered fiber illuminator for epi-fluorescence observation, with variable light intensity and shutter control, provide excellent flexibility. Lamp centering and focus adjustment are not necessary.

*L300N/L300ND/L200ND only

Filter blocks

For epi-fluorescence observation

- EPI-FL UV-2A
- EPI-FL B-2A
- EPI-FL V-2A
- EPI-FL G-2A
- EPI-FL BV-2A



*L300N/L300ND/L200ND only. Only one cube is attachable.

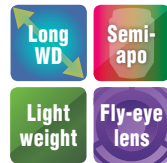
Accessories

Objective lenses

Standard objective lenses

TU Plan Fluor Series

EPI/BD 5x/10x/20x/50x/100x



Enable brightfield, darkfield, simple polarizing, sensitive polarizing, differential interference, and epi-fluorescence observations with just one lens. Achieves superior chromatic aberration performance with long working distance for all magnifications to adapt to any application.



*Brightfield observation (EPI) objective lens

Model	Magnification	NA	Working Distance (mm)
TU Plan Fluor EPI (brightfield type)	5x	0.15	23.5
	10x	0.30	17.5
	20x	0.45	4.5
	50x	0.80	1.0
TU Plan Fluor BD (brightfield/ darkfield type)	5x	0.15	18.0
	10x	0.30	15.0
	20x	0.45	4.5
	50x	0.80	1.0
	100x	0.90	1.0

Long working distance objective lenses

TU Plan ELWD Series

EPI/BD 20x/50x/100x



With the phase Fresnel lenses, these objective lenses enable long working distances while offering higher level chromatic aberration correction than conventional objective lenses. This improves operability for samples with different heights.



*Brightfield observation (EPI) objective lens

Model	Magnification	NA	Working Distance (mm)
TU Plan EPI ELWD (brightfield type)	20x	0.4	19.0
	50x	0.6	11.0
	100x	0.8	4.5
TU Plan BD ELWD (brightfield/ darkfield type)	20x	0.4	19.0
	50x	0.6	11.0
	100x	0.8	4.5

Low-magnification objective lenses

T Plan EPI

EPI 1x/2.5x



Model	Magnification	NA	Working Distance (mm)
T Plan EPI (brightfield type)	1x	0.03	3.8
	2.5x	0.075	6.5

Apochromatic objective lenses

TU Plan Apo Series

EPI/BD 50x/100x/150x



By using phase Fresnel lenses, these objective lenses achieve significantly longer operating distances while maintaining the superior chromatic aberration performance of apochromatic lenses.



*Brightfield observation (EPI) objective lens

Model	Magnification	NA	Working Distance (mm)
TU Plan Apo EPI (brightfield type)	50x	0.8	2.0
	100x	0.9	2.0
	150x	0.9	1.5
TU Plan Apo BD (brightfield/ darkfield type)	50x	0.8	2.0
	100x	0.9	2.0
	150x	0.9	1.5

Lenses with correction mechanism

CFI L Plan EPI CR Series

EPI 20x/50x/100x



Model	Magnification	NA	Working Distance (mm)	Glass Thickness Correction Range (mm)
CFI L Plan EPI CR	20x	0.45	10.9-10.0	0-1.2
CFI L Plan EPI CR	50x	0.7	3.9-3.0	0-1.2
CFI L Plan EPI CRA	100x	0.85	1.2-0.85	0-0.7
CFI L Plan EPI CRB	100x	0.85	1.3-0.95	0.6-1.3

Digital cameras

Microscope camera

DS-Fi3

Three main features of the previous models, high-resolution, high sensitivity and low noise, and high-speed live display are offered in 1 camera.



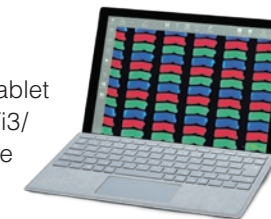
Frame Rate	30fps (1440x1024)	45fps (1636x1088)
Max Recordable Pixels	2880x2048	4908x3264

Imaging software NIS-Elements

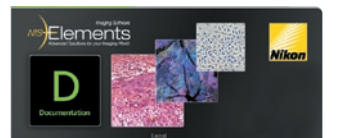
Using a tablet PC



Simply installing NIS-Elements L on a tablet PC enables setting and control of DS-Fi3/DS-Ri2 microscope cameras, live image display, and image acquisition.



Using a desktop PC



A wide variety of tools

NIS-Elements L enables the conducting of simple measurements on images, with input of lines and comments. These can also be written onto and saved with the image, and measurement data can be output.

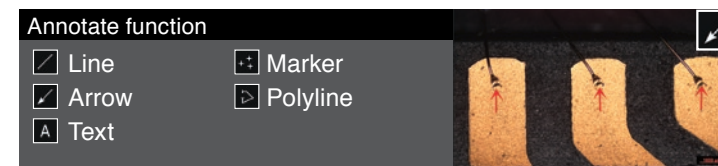
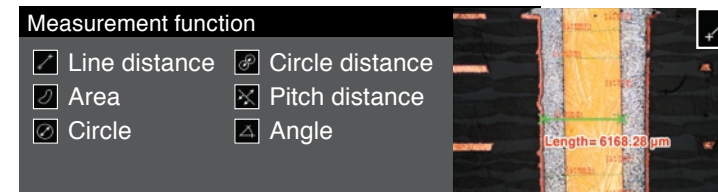
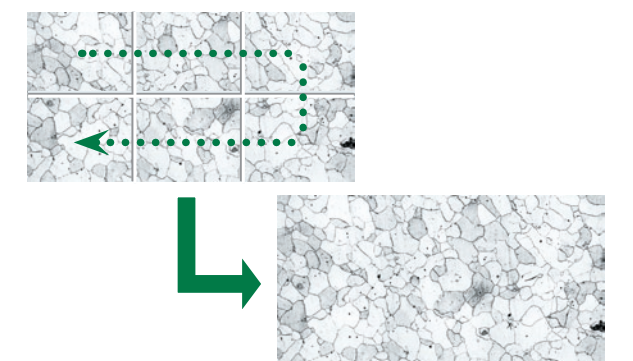


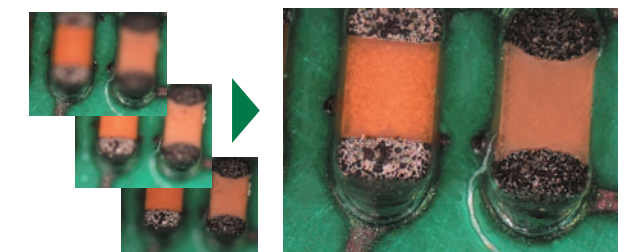
Image Stitching

Stitches together images acquired from multiple fields of view to create one image.



EDF (Extended Depth of Focus)

Create a single, all-in-focus image from images of differing focus.



Scene Mode

Ten camera setting patterns for optimal color reproduction and contrast for each microscope light source, observation method and type of sample, as well as custom settings, can be selected.

- Wafer/IC
- Metal, Ceramic/Plastic
- Circuit board
- Flat Panel Display

* See the "Digital Camera Digital Sight Series for Microscopes" catalog for details on Digital Sight features.

Wafer loader NWL200

Combined with the NWL200 wafer loader, the ECLIPSE L200N meets requirements for wafer inspections.

Support for ultra-thin 100 μm wafers

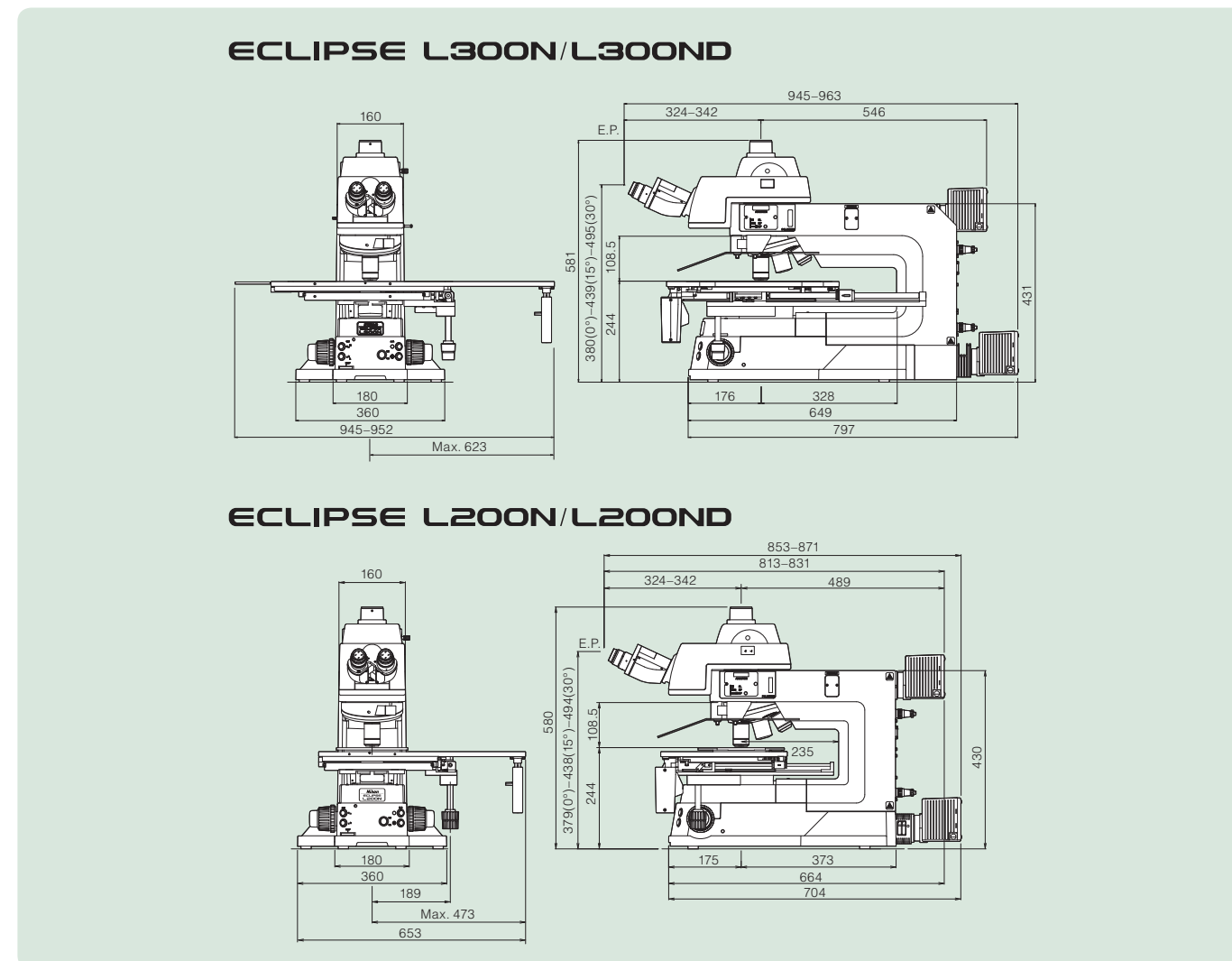
- NWL200 series provides levels of safety and reliability that meet all requirements for inspection of the latest wafers.

Improved operability and high throughput

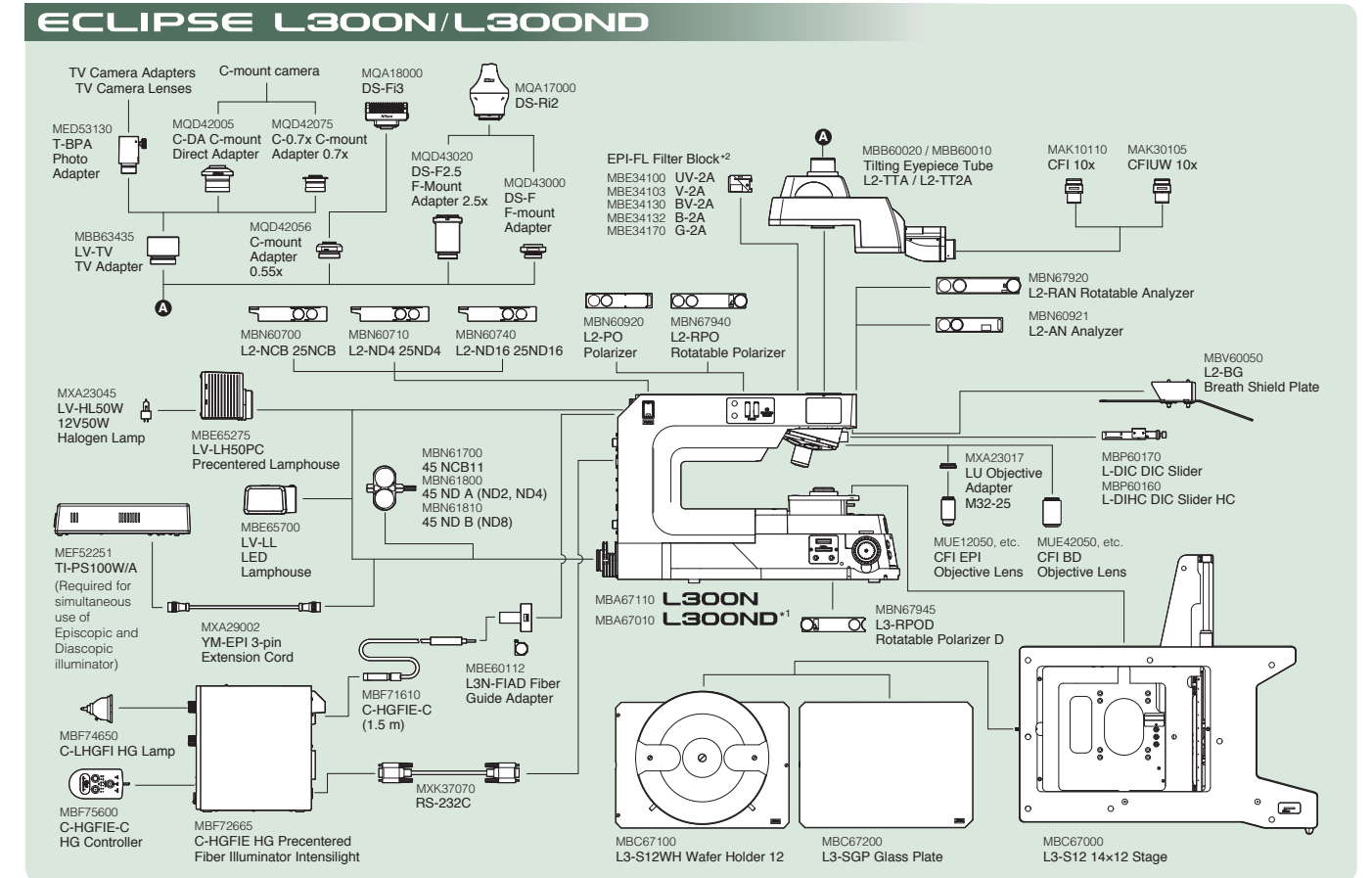
- Setting conditions, such as sampling and inspection patterns, and checking the operating status and content of errors can easily be done with the large LCD panel
- Comprehensive file management functions for carriers and samples are useful for automating inspections
- Exceptionally fast elevator, and the loading and unloading of wafers with complete precision by the multi-arm system all contribute to an efficient wafer transfer and exchange



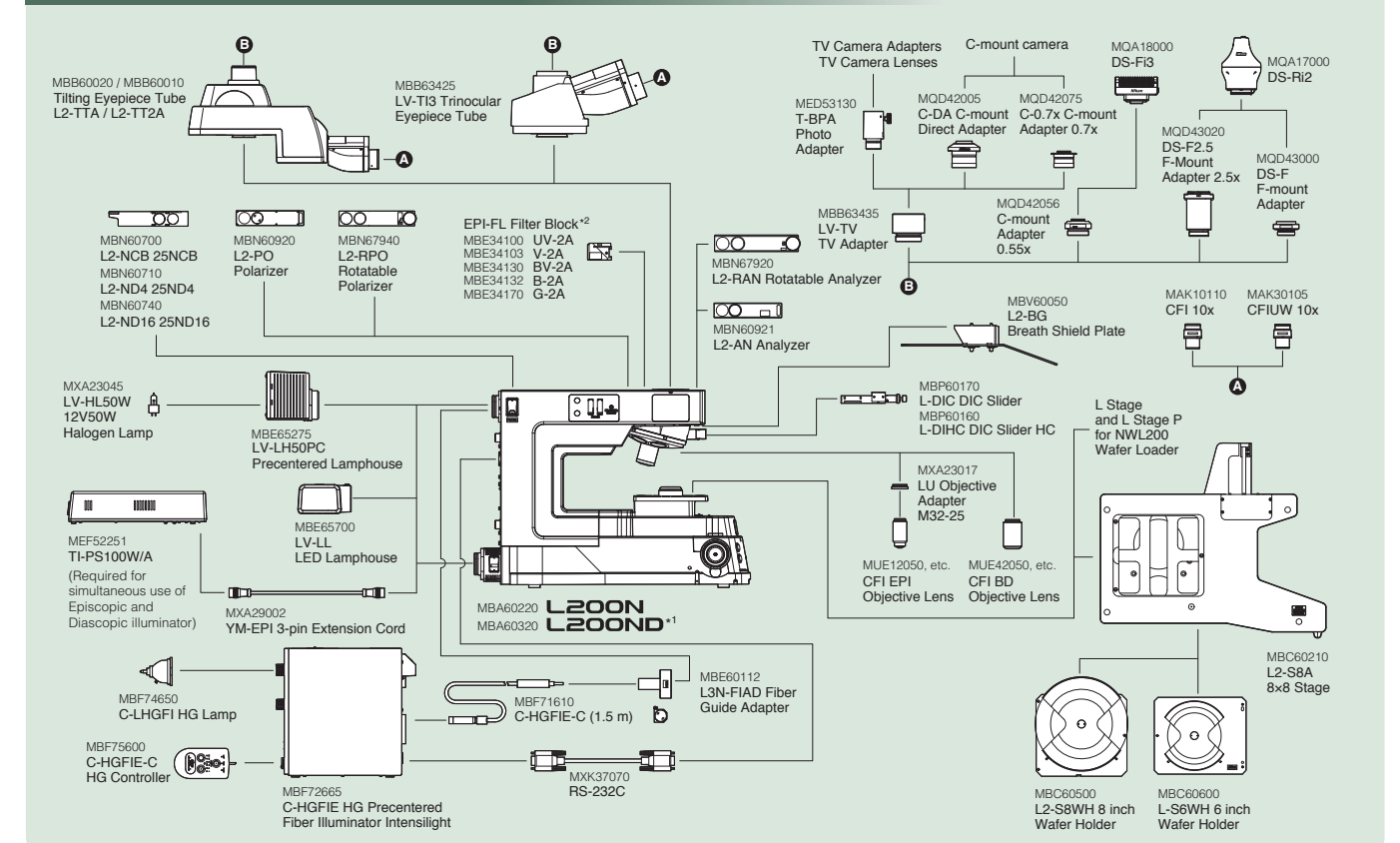
Dimensional diagram (Unit: mm)



System diagram



ECLIPSE L200N/L200ND



*1 Diascopic illumination available only for L300ND and L200ND
 *2 Epi-fluorescence observation available only for L300ND/L300N/L200ND

Specifications

		ECLIPSE L300N	ECLIPSE L200N	ECLIPSE L300ND	ECLIPSE L200ND
Illumination type		Episcopic		Episcopic/Diascopic	
Main body		Power sources for motorized control built in Motorized control for nosepiece, Light intensity control, Aperture diaphragm control			
Nosepiece		Motorized universal sextuple nosepiece			
	Centering Function	Yes	—	Yes	—
	EPI/DIA changeover	—	—	Yes	
Focusing mechanism	Cross travel	29 mm			
	Coarse	12.7 mm per rotation (torque adjustable, refocusing mechanism provided)			
	Fine	0.1 mm per rotation (in 1 µm increments)			
Episcopic illuminator		12V-50W halogen lamp light source built in, LV-LL LED Lamphouse Motorized aperture diaphragm (centerable), Fixed field diaphragm (with focus target) Pinhole slider (optional), Four ø25 mm filters (NCB11, ND16, ND4), Polarizer and Analyzer can be mounted Observation methods: Brightfield, Darkfield, Simple polarizing, DIC, Epi-fluorescence* (*L300N/L300ND/L200ND only)			
Diascopic illuminator		—		12V-50W halogen lamp light source built in, LV-LL LED Lamphouse Aperture diaphragm built in LWD condenser built in	
Interface		USB x 1, RS232C (for Intensilight) x 1			
Eyepiece tubes		L2-TT2A Ultra-widefield erect-image tilting trinocular eyepiece tube (tilt angle: 0-30 °) FOV: 22/25; Beam split ratio 100:0/20:80 L2-TTA Ultra-widefield erect-image tilting trinocular eyepiece tube (tilt angle: 0-30 °) FOV: 22/25; Beam split ratio 100:0/0:100 LV-TI3 Trinocular eyepiece tube (erect image) FOV: 22/25; Beam split ratio 100:0/0:100			
Eyepieces		CFI eyepiece lens series			
Objective lenses		CFI ₆₀ -2/CFI ₆₀ system			
Stages		14 x 12 stage	L2-S8A 8 x 8 stage	14 x 12 stage	L2-S8A 8 x 8 stage
	Stroke	354 x 302 mm	205 x 205 mm	354 x 302 mm	205 x 205 mm
	Diascopic observation range	354 x 268 mm	150 x 150 mm	354 x 268 mm	150 x 150 mm
		Coarse/Fine-movement changeover possible Fixed-position X-Y fine-movement controls			
Antistatic mechanism		1000-10 V, within 0.2 sec			
Power consumption		1.2 A/90 W			
Weight (approx.)	Body only	40 kg	30 kg	40 kg	30 kg
	With L2-S8A 8 x 8 stage and L2-TTA eyepiece tube	45 kg	45 kg	45 kg	45 kg

Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. July 2019 ©2010-2019 NIKON CORPORATION

N.B. Export of the products* in this brochure is controlled under the Japanese Foreign Exchange and Foreign Trade Law. Appropriate export procedures shall be required in case of export from Japan.

*Products: Hardware and its technical information (including software)

WARNING TO ENSURE CORRECT USAGE, READ THE CORRESPONDING MANUALS CAREFULLY BEFORE USING THE EQUIPMENT.



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